

December 2013

# FCD9N60NTM

# N-Channel SupreMOS<sup>®</sup> MOSFET 600 V, 9 A, 385 m $\Omega$

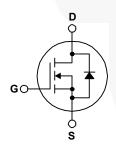
#### **Features**

- $R_{DS(on)} = 330 \text{ m}\Omega \text{ (Typ.)} @ V_{GS} = 10 \text{ V, } I_D = 4.5 \text{ A}$
- Ultra Low Gate Charge (Typ. Q<sub>q</sub> = 17.8 nC)
- · Low Effective Output Capacitance
- 100% Avalanche Tested
- · RoHS Compliant

### Description

The SupreMOS® MOSFET is Fairchild Semiconductor's next generation of high voltage super-junction (SJ) technology employing a deep trench filling process that differentiates it from the conventional SJ MOSFETs. This advanced technology and precise process control provides lowest Rsp on-resistance, superior switching performance and ruggedness. SupreMOS MOSFET is suitable for high frequency switching power converter applications such as PFC, server/telecom power, FPD TV power, ATX power, and industrial power applications.





## **MOSFET Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol		Parameter		FCD9N60NTM	Unit
V <sub>DSS</sub>	Drain to Source Volta	Drain to Source Voltage		600	V
$V_{GSS}$	Gate to Source Voltage	је		±30	V
	Drain Current	- Continuous (T <sub>C</sub>	= 25°C)	9.0	A
I <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub>	= 100°C)	5.7	A
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	27	Α
E <sub>AS</sub>	Single Pulsed Avaland	Single Pulsed Avalanche Energy (Note 2)		135	mJ
I <sub>AR</sub>	Avalanche Current	rrent (Note 1)		9.0	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		(Note 1)	9.3	mJ
dv/dt	MOSFET dv/dt Rugge	edness		100	V/ns
uv/ut	Peak Diode Recovery	dv/dt	(Note 3)	15	V/115
C	Dower Dissipation	$(T_C = 25^{\circ}C)$		92.6	W
$P_{D}$	Power Dissipation	- Derate above 25		0.74	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storag	ge Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		Purpose,	300	°C

#### **Thermal Characteristics**

Symbol	Parameter	FCD9N60NTM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.35	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	10/00

# **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCD9N60NTM	FCD9N60NTM	D-PAK	Tape and Reel	330 mm	16 mm	2500 units

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 1 \text{mA}, V_{GS} = 0 \text{V}, T_J = 25^{\circ} \text{C}$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1mA, Referenced to 25°C	-	0.8	-	V/°C
1	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 480V, V <sub>GS</sub> = 0V	-	-	10	μА
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 480V, V_{GS} = 0V, T_{C} = 125^{\circ}C$	-	-	100	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 4.5A	-	0.330	0.385	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 40V, I_{D} = 4.5A$	ı	5.3	-	S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 400V V 0V	-	735	1000	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 100V, V_{GS} = 0V$ f = 1MHz	-	40	53	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	I - HVIIIZ	-	3.5	5.5	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380V, V_{GS} = 0V, f = 1MHz$	-\	23.7	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	$V_{DS} = 0V \text{ to } 380V, V_{GS} = 0V$	- \	122	-	pF

### **Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time			-	13.2	-	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 380V, I_{D} = 4.5A$		-	9.6	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{GEN} = 4.7\Omega$		-	28.7	-	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4)	-	11.5	-	ns
Q <sub>g(tot)</sub>	Total Gate Charge at 10V			- /	17.8	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS} = 380V, I_{D} = 4.5A$		-/	4.2	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V	(Note 4)	-	7.6	-	nC
ESR	Equivalent Series Resistance(G-S)	f = 1MHz		/-	2.65	-	Ω

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diod	Maximum Continuous Drain to Source Diode Forward Current				Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			27	/ -	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 9A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 9A	-	322	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	5.04	-	μС

#### Notes

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
- 2. I<sub>AS</sub> = 3 A, R<sub>G</sub> = 25  $\Omega$ , starting T<sub>J</sub> = 25°C.
- $3.I_{SD} \le 9$  A, di/dt  $\le 200$  A/ $\mu$ s,  $V_{DD} \le 380$  V, starting  $T_J$  =  $25^{\circ}C$ .
- ${\bf 4.} \ Essentially \ independent \ of \ operating \ temperature \ typical \ characteristics.$

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

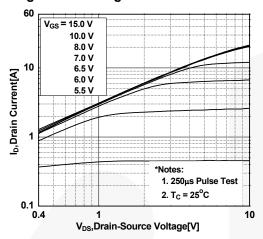


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

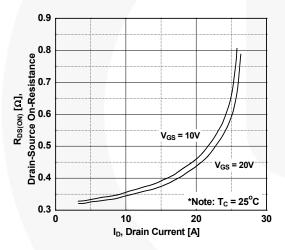


Figure 5. Capacitance Characteristics

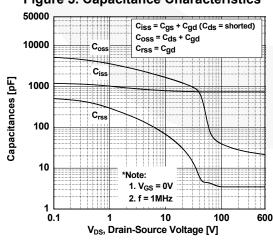


Figure 2. Transfer Characteristics

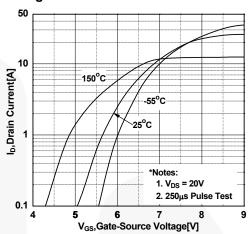


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

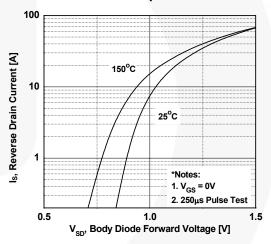
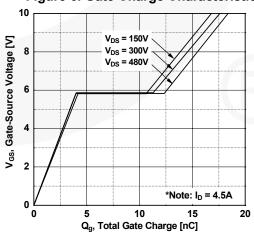


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

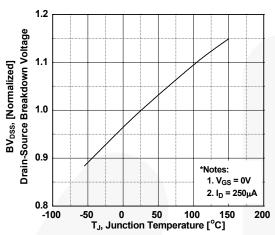


Figure 9. Maximum Safe Operating Area

vs. Temperature 3.0

Figure 8. On-Resistance Variation

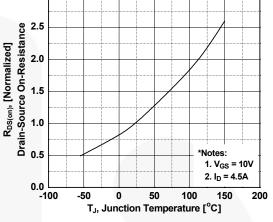
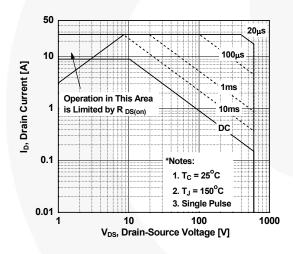


Figure 10. Maximum Drain Current vs. Case Temperature



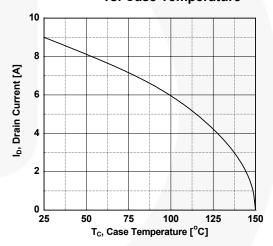
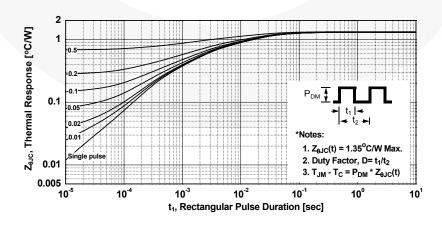


Figure 11. Transient Thermal Response Curve



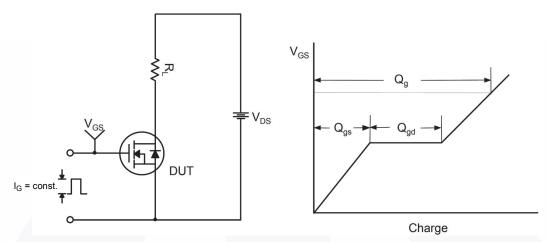


Figure 12. Gate Charge Test Circuit & Waveform

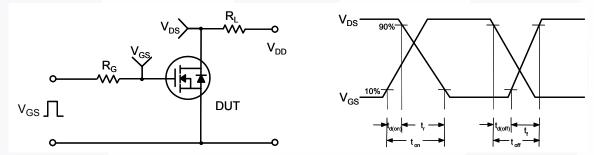


Figure 13. Resistive Switching Test Circuit & Waveforms

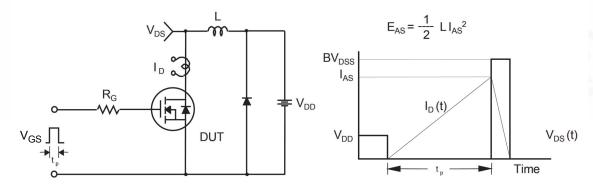


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

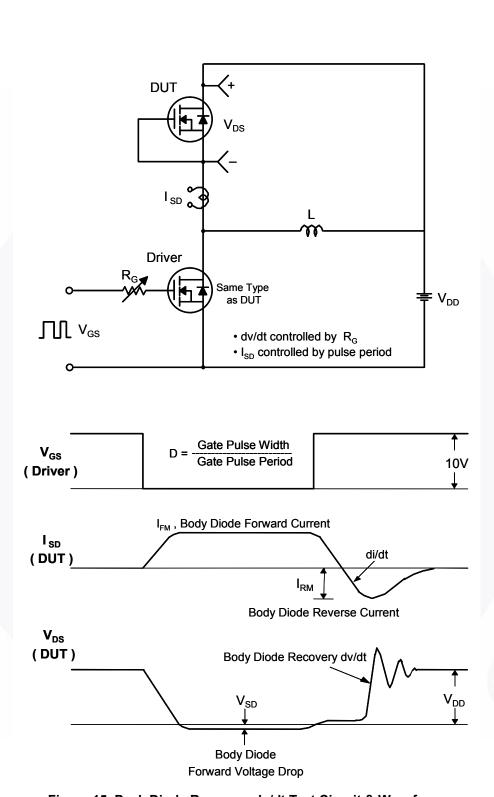


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

#### **Mechanical Dimensions**

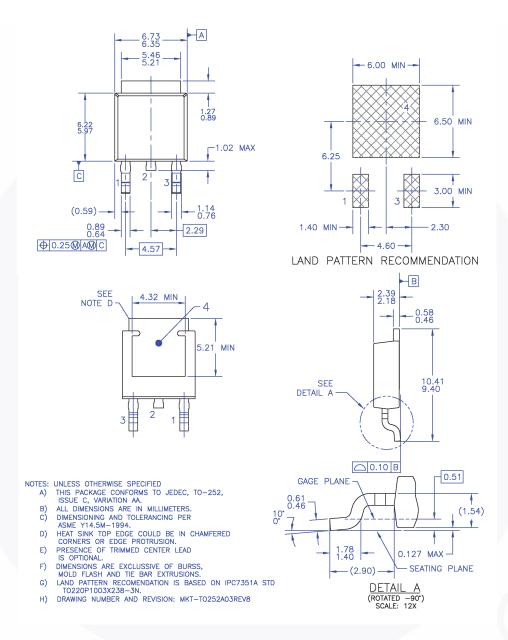


Figure 16. TO252 (D-PAK), Molded, 3-Lead, Option AA&AB

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